

SWRS116F - AUGUST 2011 - REVISED OCTOBER 2014

CC1175 High-Performance RF Transmitter for Narrowband Systems

1 Device Overview

INSTRUMENTS

1.1 Features

Texas

- · High-Performance, Single-Chip Transmitter
 - Very Low Phase Noise: –111 dBc/Hz at 10-kHz Offset
- High Spectral Efficiency (9.6 kbps in 12.5-kHz Channel in Compliance With FCC Narrowbanding Mandate)
- 128-Byte TX FIFO
- Support for Seamless Integration With the CC1190 Device for Increased Range Giving up to +27-dBm Output Power
- Programmable Output Power up to +16 dBm With 0.4-dB Step Size
- Power Supply
 - Wide Supply Voltage Range (2.0 V to 3.6 V)
 - Low Current Consumption:
 - TX: 45 mA at +14 dBm
 - Power Down: 0.12 μA (0.5 μA With Timer Running)

1.2 Applications

- One-way Narrowband Ultra-Low Power Wireless Systems With Channel Spacing Down to 6.25 kHz
- 169-, 315-, 433-, 868-, 915-, 920-, 950-MHz ISM/SRD Band Systems
- Wireless Metering and Wireless Smart Grid (AMR and AMI)

- · Automatic Output Power Ramping
- Configurable Data Rates: 0 to 200 kbps
- Supported Modulation Formats: 2-FSK, 2-GFSK, 4-FSK, 4-GFSK, MSK, OOK
- RoHS-Compliant 5-mm x 5-mm No-Lead QFN 32-Pin Package (RHB)
- Regulations Suitable for Systems Targeting Compliance With
 - Europe: ETSI EN 300 220, ETSI EN 54-25
 - US: FCC CFR47 Part 15, FCC CFR47 Part 90, 24, and 101
 - Japan: ARIB RCR STD-T30, ARIB STD-T67, ARIB STD-T108
- Peripherals and Support Functions
 - TCXO Support and Control, also in Power Modes
 - Optional Coding Gain Feature for Increased Range and Robustness
 - Temperature Sensor
- IEEE 802.15.4g Systems
- Home and Building Automation
- · Wireless Alarm and Security Systems
- Industrial Monitoring and Control
- Wireless Healthcare Applications
- · Wireless Sensor Networks and Active RFID

1.3 Description

The CC1175 device is a fully integrated single-chip radio transmitter designed for high performance at very low-power and low-voltage operation in cost-effective wireless systems. All filters are integrated, thus removing the need for costly external SAW and IF filters. The device is mainly intended for the ISM (Industrial, Scientific, and Medical) and SRD (Short Range Device) frequency bands at 164–192 MHz, 274–320 MHz, 410–480 MHz, and 820–960 MHz.

The CC1175 device provides extensive hardware support for packet handling, data buffering, and burst transmissions. The main operating parameters of the CC1175 device can be controlled through an SPI interface. In a typical system, the CC1175 device will be used with a microcontroller and only a few external passive components.

Device Information⁽¹⁾

| PART NUMBER | PACKAGE | BODY SIZE |
|-------------|-----------|-------------------|
| CC1175RHB | VQFN (32) | 5.00 mm x 5.00 mm |

(1) For more information, see Section 8, Mechanical Packaging and Orderable Information



1.4 Functional Block Diagram

Figure 1-1 shows the system block diagram of the CC1175 device.

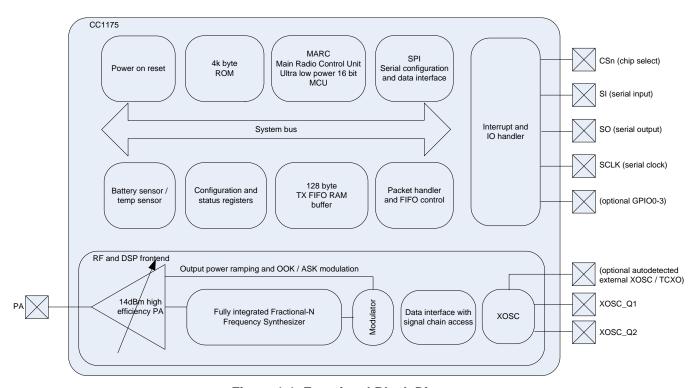


Figure 1-1. Functional Block Diagram



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2 Revision History

NOTE: Page numbers for previous revisions may differ from page numbers in the current version.

This data manual revision history highlights the changes made to the SWRS116E device-specific data manual to make it an SWRS116F revision.

| Chang | ges from Revision E (June 2014) to Revision F | Page |
|-------|--|------|
| | Added Ambient to the temperature range condition and removed Tj from Temperature range | _ |



3 Terminal Configuration and Functions

3.1 Pin Diagram

Figure 3-1 shows pin names and locations for the CC1175 device.

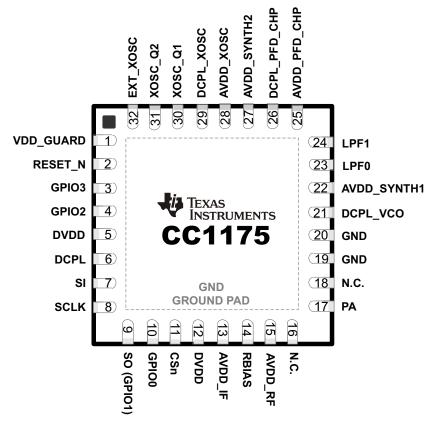


Figure 3-1. Package 5-mm × 5-mm QFN



3.2 Pin Configuration

The following table lists the pin-out configuration for the CC1175 device.

| PIN NO. | PIN NAME | n-out configuration for the CO | DESCRIPTION |
|---------|--------------|--------------------------------|--|
| 1 | VDD_GUARD | Power | 2.0-3.6 V VDD |
| 2 | RESET_N | Digital input | Asynchronous, active-low digital reset |
| 3 | GPIO3 | Digital I/O | General-purpose I/O |
| 4 | GPIO2 | Digital I/O | General-purpose I/O |
| 5 | DVDD | Power | 2.0–3.6 VDD to internal digital regulator |
| 6 | DCPL | Power | Digital regulator output to external decoupling capacitor |
| 7 | SI | Digital input | Serial data in |
| 8 | SCLK | Digital input | Serial data clock |
| 9 | SO(GPIO1) | Digital I/O | Serial data out (general-purpose I/O) |
| 10 | GPIO0 | Digital I/O | General-purpose I/O |
| 11 | CSn | Digital input | Active-low chip select |
| 12 | DVDD | Power | 2.0–3.6 V VDD |
| 13 | AVDD_IF | Power | 2.0-3.6 V VDD |
| 14 | RBIAS | Analog | External high-precision resistor |
| 15 | AVDD_RF | Power | 2.0-3.6 V VDD |
| 16 | N.C. | | Not connected |
| 17 | PA | Analog | Single-ended TX output (requires DC path to VDD) |
| 18 | N.C. | | Not connected |
| 19 | GND1 | Analog | Analog ground |
| 20 | GND0 | Analog | Analog ground |
| 21 | DCPL_VCO | Power | Pin for external decoupling of VCO supply regulator |
| 22 | AVDD_SYNTH1 | Power | 2.0-3.6 V VDD |
| 23 | LPF0 | Analog | External loop filter components |
| 24 | LPF1 | Analog | External loop filter components |
| 25 | AVDD_PFD_CHP | Power | 2.0–3.6 V VDD |
| 26 | DCPL_PFD_CHP | Power | Pin for external decoupling of PFD and CHP regulator |
| 27 | AVDD_SYNTH2 | Power | 2.0-3.6 V VDD |
| 28 | AVDD_XOSC | Power | 2.0-3.6 V VDD |
| 29 | DCPL_XOSC | Power | Pin for external decoupling of XOSC supply regulator |
| 30 | XOSC_Q1 | Analog | Crystal oscillator pin 1 (must be grounded if a TCXO or other external clock connected to EXT_XOSC is used) |
| 31 | XOSC_Q2 | Analog | Crystal oscillator pin 2 (must be left floating if a TCXO or other external clock connected to EXT_XOSC is used) |
| 32 | EXT_XOSC | Digital input | Pin for external clock input (must be grounded if a regular crystal connected to XOSC_Q1 and XOSC_Q2 is used) |
| _ | GND | Ground pad | The ground pad must be connected to a solid ground plane. |



4 Specifications

All measurements performed on CC1120EM_868_915 rev.1.0.1, CC1120EM_955 rev.1.2.1, CC1120EM_420_470 rev.1.0.1, or CC1120EM_169 rev.1.2.

4.1 Absolute Maximum Ratings⁽¹⁾⁽²⁾

| PARAMETER | MIN | MAX | UNIT | CONDITION |
|--|------|---------|------|--|
| Supply voltage (VDD, AVDD_x) | -0.3 | 3.9 | V | All supply pins must have the same voltage |
| Voltage on any digital pin | -0.3 | VDD+0.3 | V | max 3.9 |
| Voltage on analog pins (including DCPL pins) | -0.3 | 2.0 | V | |

⁽¹⁾ Stresses beyond those listed under absolute maximum ratings may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated under general characteristics is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

4.2 Handling Ratings

| | | | | MIN | MAX | UNIT |
|------------------|------------------------------|--|-------------------|------|-----|------|
| T _{stg} | Storage temperature range | | | | 125 | °C |
| | | Human body model (HBM), per ANSI/ESDA/JEDEC JS00 |)1 ⁽¹⁾ | -2 | 2 | kV |
| V _{ESD} | discharge (ESD) performance: | Charged device model (CDM), per JESD22-C101 ⁽²⁾ | All pins | -500 | 500 | V |

⁽¹⁾ JEDEC document JEP155 states that 500-V HBM allows safe manufacturing with a standard ESD control process.

4.3 Recommended Operating Conditions (General Characteristics)

| PARAMETER | MIN | TYP | MAX | UNIT | CONDITION |
|---------------------------|-----|-----|-----|------|--|
| Voltage supply range | 2.0 | | 3.6 | V | All supply pins must have the same voltage |
| Voltage on digital inputs | 0 | | VDD | V | |
| Temperature range | -40 | | 85 | °C | Ambient |

4.4 Thermal Resistance Characteristics for RHB Package

| | | °C/W ⁽¹⁾ | AIR FLOW (m/s) ⁽²⁾ |
|-------------------|---------------------------|---------------------|-------------------------------|
| $R\theta_{JC}$ | Junction-to-case (top) | 21.1 | 0.00 |
| $R\theta_{JB}$ | Junction-to-board | 5.3 | 0.00 |
| $R\theta_{JA}$ | Junction-to-free air | 31.3 | 0.00 |
| Psi _{JT} | Junction-to-package top | 0.2 | 0.00 |
| Psi _{JB} | Junction-to-board | 5.3 | 0.00 |
| $R\theta_{JC}$ | Junction-to-case (bottom) | 0.8 | 0.00 |

⁽¹⁾ These values are based on a JEDEC-defined 2S2P system (with the exception of the Theta JC [RΘ_{JC}] value, which is based on a JEDEC-defined 1S0P system) and will change based on environment as well as application. For more information, see these EIA/JEDEC standards:

- JESD51-2, Integrated Circuits Thermal Test Method Environmental Conditions Natural Convection (Still Air)
- JESD51-3, Low Effective Thermal Conductivity Test Board for Leaded Surface Mount Packages
- JESD51-7, High Effective Thermal Conductivity Test Board for Leaded Surface Mount Packages
- JESD51-9, Test Boards for Area Array Surface Mount Package Thermal Measurements

Power dissipation of 40 mW and an ambient temperature of 25°C is assumed.

(2) m/s = meters per second

⁽²⁾ All voltage values are with respect to V_{SS}, unless otherwise noted.

⁽²⁾ JEDEC document JEP157 states that 250-V HBM allows safe manufacturing with a standard ESD control process.



4.5 RF Characteristics

| PARAMETER | MIN | TYP | MAX | UNIT | CONDITION |
|----------------------|---------|------|-------|------|---|
| | 820 | | 960 | MHz | |
| | 410 | | 480 | MHz | |
| Frequency bands | (273.3) | | (320) | MHz | For more information, see SWRA398, Using the CC112x/CC1175 at 274 to 320 MHz. |
| | 164 | | 192 | MHz | |
| | (205) | | (240) | MHz | Contact TI for more |
| | (136.7) | | (160) | MHz | information about the use of these frequency bands. |
| | | 30 | | Hz | In 820- to 960-MHz band |
| Frequency resolution | | 15 | | Hz | In 410- to 480-MHz band |
| | | 6 | | Hz | In 164- to 192-MHz band |
| Data vala | 0 | | 200 | kbps | Packet mode |
| Data rate | 0 | | 100 | kbps | Transparent mode |
| Data rate step size | | 1e-4 | | bps | |



4.6 Regulatory Standards

| PERFORMANCE MODE | FREQUENCY BAND | SUITABLE FOR COMPLIANCE WITH | COMMENTS |
|-----------------------|----------------|------------------------------|---|
| | | ARIB T-108 | |
| | | ARIB T-96 | |
| | | ETSI EN 300 220 | |
| | | ETSI EN 54-25 | Performance also suitable for systems targeting maximum |
| | 820–960 MHz | FCC Part 101 | allowed output power in the |
| | 820–960 MH2 | FCC Part 24 Submask D | respective bands, using a range extender such as the CC1190 |
| | | FCC Part 15.247 | device |
| | | FCC Part 15.249 | |
| | | FCC Part 90 Mask G | |
| High-performance mode | | FCC Part 90 Mask J | |
| | | ARIB T-67 | |
| | 410–480 MHz | ARIB RCR STD-30 | Performance also suitable for systems targeting maximum |
| | | ETSI EN 300 220 | allowed output power in the |
| | | FCC Part 90 Mask D | respective bands, using a range extender |
| | | FCC Part 90 Mask G | SACTION . |
| | | ETSI EN 300 220 | Performance also suitable for |
| | 164–192 MHz | FCC Part 90 Mask D | systems targeting maximum allowed output power in the respective bands, using a range extender |
| | | ETSI EN 300 220 | |
| | 820–960 MHz | FCC Part 15.247 | |
| Low-power mode | | FCC Part 15.249 | |
| | 410–480 MHz | ETSI EN 300 220 | |
| | 164–192 MHz | ETSI EN 300 220 | |

4.7 Current Consumption, Static Modes

 $T_A = 25$ °C, VDD = 3.0 V if nothing else is stated

| PARAMETER | MIN | TYP | MAX | UNIT | CONDITION |
|---------------------------|-----|------|-----|------|--|
| | | 0.12 | 1 | μA | |
| Power down with retention | | 0.5 | | μA | Low-power RC oscillator running |
| XOFF mode | | 170 | | μA | Crystal oscillator / TCXO disabled |
| IDLE mode | | 1.3 | | mA | Clock running, system waiting with no radio activity |



4.8 **Current Consumption, Transmit Modes**

4.8.1 950-MHz Band (High-Performance Mode)

 $T_A = 25$ °C, VDD = 3.0 V if nothing else is stated

| PARAMETER | MIN | TYP | MAX | UNIT | CONDITION |
|--------------------------------|-----|-----|-----|------|-----------|
| TX current consumption +10 dBm | | 37 | | mA | |
| TX current consumption 0 dBm | | 26 | | mA | |

4.8.2 868-, 915-, and 920-MHz Bands (High-Performance Mode)

 $T_A = 25$ °C, VDD = 3.0 V if nothing else is stated

| PARAMETER | MIN | TYP | MAX | UNIT | CONDITION |
|--------------------------------|-----|-----|-----|------|-----------|
| TX current consumption +14 dBm | | 45 | | mA | |
| TX current consumption +10 dBm | | 34 | | mA | |

4.8.3 434-MHz Band (High-Performance Mode)

 $T_{\Lambda} = 25^{\circ}C$. VDD = 3.0 V if nothing else is stated

| PARAMETER | MIN | TYP | MAX | UNIT | CONDITION |
|--------------------------------|-----|-----|-----|------|-----------|
| TX current consumption +15 dBm | | 50 | | mA | |
| TX current consumption +14 dBm | | 45 | | mA | |
| TX current consumption +10 dBm | | 34 | | mA | |

4.8.4 169-MHz Band (High-Performance Mode)

 $T_A = 25^{\circ}C$. VDD = 3.0 V if nothing else is stated

| PARAMETER | MIN | TYP | MAX | UNIT | CONDITION |
|--------------------------------|-----|-----|-----|------|-----------|
| TX current consumption +15 dBm | | 54 | | mA | |
| TX current consumption +14 dBm | | 49 | | mA | |
| TX current consumption +10 dBm | | 41 | | mA | |

4.8.5 Low-Power Mode

 $T_A = 25$ °C. VDD = 3.0 V. $f_C = 869.5$ MHz if nothing else is stated

| PARAMETER | MIN | TYP | MAX | UNIT | CONDITION |
|--------------------------------|-----|-----|-----|------|-----------|
| TX current consumption +10 dBm | | 32 | | mA | |



4.9 Transmit Parameters

 $T_A = 25$ °C, VDD = 3.0 V, $f_c = 869.5$ MHz if nothing else is stated

| PARAMETER | MIN | TYP | MAX | UNIT | CONDITION |
|--|-----|----------|-----|--------|---|
| | | +12 | | dBm | At 950 MHz |
| | | +14 | | dBm | At 915 and 920 MHz |
| | | +15 | | dBm | At 915 and 920 MHz with VDD = 3.6 V |
| | | +15 | | dBm | At 868 MHz |
| Max output power | | +16 | | dBm | At 868 MHz with VDD = 3.6 V |
| | | +15 | | dBm | At 433 MHz |
| | | +16 | | dBm | At 433 MHz with VDD = 3.6 V |
| | | +15 | | dBm | At 169 MHz |
| | | +16 | | dBm | At 169 MHz with VDD = 3.6 V |
| Min output nouse | | -11 | | dBm | Within fine step size range |
| Min output power | | -40 | | dBm | Within coarse step size range |
| Output power step size | | 0.4 | | dB | Within fine step size range |
| | | -75 | | dBc | 4-GFSK 9.6 kbps in 12.5-kHz channel, measured in 100-Hz bandwidth at 434 MHz (FCC Part 90 Mask D compliant) |
| Adjacent channel power | | -58 | | dBc | 4-GFSK 9.6 kbps in 12.5-kHz channel, measured in 8.75-kHz bandwidth (ETSI–300 220 compliant) |
| | | -61 | | dBc | 2-GFSK 2.4 kbps in 12.5-kHz channel, 1.2-kHz deviation |
| Spurious emissions (Not including harmonics) | | <-60 | | dBm | |
| Harmonics | | | | | |
| Second Harm, 169 MHz | | -39 | | dBm | |
| Third Harm, 169 MHz | | -58 | | dBm | |
| Second Harm, 433 MHz | | -56 | | dBm | Transmission at +14 dBm (or maximum |
| Third Harm, 433 MHz | | -51 | | dBm | allowed in applicable band where this is less than +14 dBm) using TI reference design |
| Second Harm, 450 MHz | | -60 | | dBm | Emissions measured according to ARIB T- |
| Third Harm, 450 MHz | | -45 | | dBm | 96 in 950-MHz band, ETSI EN 300 220 in 169-, 433-, and 868-MHz bands and FCC |
| Second Harm, 868 MHz | | -40 | | dBm | Part 15.247 in 450- and 915-MHz band |
| Third Harm, 868 MHz | | -42 | | dBm | Fourth harmonic in 915-MHz band will |
| Second Harm, 915 MHz | | 56 | | dBuV/m | require extra filtering to meet FCC requirements if transmitting for long intervals |
| Third Harm, 915 MHz | | 52 | | dBuV/m | (>50-ms periods). |
| Fourth Harm, 915 MHz | | 60 | | dBuV/m | |
| Second Harm, 950 MHz | | -58 | | dBm | |
| Third Harm, 950 MHz | | -42 | | dBm | |
| Optimum load impedance | | | | | |
| 868-, 915-, and 920-MHz bands | | 35 + j35 | | Ω | |
| 433-MHz band | | 55 + j25 | | Ω | |
| 169-MHz band | | 80 + j0 | | Ω | |



4.10 PLL Parameters

4.10.1 High-Performance Mode

 $T_A = 25$ °C, VDD = 3.0 V, $f_c = 869.5$ MHz if nothing else is stated

| PARAMETER | MIN | TYP | MAX | UNIT | CONDITION |
|--|-----|------|-----|--------|------------------|
| | | -99 | | dBc/Hz | ± 10 kHz offset |
| Phase noise in 950-MHz band | | -99 | | dBc/Hz | ± 100 kHz offset |
| | | -123 | | dBc/Hz | ± 1 MHz offset |
| | | -99 | | dBc/Hz | ± 10 kHz offset |
| Phase noise in 868-, 915-, and 920-MHz bands | | -100 | | dBc/Hz | ± 100 kHz offset |
| bando | | -122 | | dBc/Hz | ± 1 MHz offset |
| | | -106 | | dBc/Hz | ± 10 kHz offset |
| Phase noise in 433-MHz band | | -107 | | dBc/Hz | ± 100 kHz offset |
| | | -127 | | dBc/Hz | ± 1 MHz offset |
| Phase noise in 169-MHz band | | -111 | | dBc/Hz | ± 10 kHz offset |
| | | -116 | | dBc/Hz | ± 100 kHz offset |
| | | -135 | | dBc/Hz | ± 1 MHz offset |

4.10.2 Low-Power Mode

 $T_A = 25$ °C, VDD = 3.0 V, $f_c = 869.5$ MHz if nothing else is stated

| PARAMETER | MIN | TYP | MAX | UNIT | CONDITION |
|---------------------------------------|-----|------|-----|--------|------------------|
| | | -90 | | dBc/Hz | ± 10 kHz offset |
| Phase noise in 950-MHz band | | -92 | | dBc/Hz | ± 100 kHz offset |
| | | -124 | | dBc/Hz | ± 1 MHz offset |
| | | -95 | | dBc/Hz | ± 10 kHz offset |
| Phase noise in 868- and 915-MHz bands | | -95 | | dBc/Hz | ± 100 kHz offset |
| | | -124 | | dBc/Hz | ± 1 MHz offset |
| | | -98 | | dBc/Hz | ± 10 kHz offset |
| Phase noise in 433-MHz band | | -102 | | dBc/Hz | ± 100 kHz offset |
| | | -129 | | dBc/Hz | ± 1 MHz offset |
| Phase noise in 169-MHz band | | -106 | | dBc/Hz | ± 10 kHz offset |
| | | -110 | | dBc/Hz | ± 100 kHz offset |
| | · | -136 | | dBc/Hz | ± 1 MHz offset |



4.11 Wake-up and Timing

 $T_A = 25$ °C, VDD = 3.0 V, $f_c = 869.5$ MHz if nothing else is stated

| PARAMETER | MIN | TYP | MAX | UNIT | CONDITION |
|-----------------------------------|-----|-----|-----|------|------------------------------------|
| Powerdown to IDLE | | 0.4 | | ms | Depends on crystal |
| IDLE to TX | | 166 | | μs | Calibration disabled |
| | | 461 | | μs | Calibration enabled |
| TX to IDLE time | | 296 | | μs | Calibrate when leaving TX enabled |
| | | 0 | | μs | Calibrate when leaving TX disabled |
| Frequency synthesizer calibration | | 391 | | μs | When using SCAL strobe |

4.12 High-Speed Crystal Oscillator

 $T_{\Lambda} = 25$ °C. VDD = 3.0 V if nothing else is stated

| 1 _A = 25 C, VDD = 5.0 V II flottilling else is stated | | | | | | | | |
|--|-----|-----|-----|------|--|--|--|--|
| PARAMETER | MIN | TYP | MAX | UNIT | CONDITION | | | |
| Crystal frequency | 32 | | 44 | MHz | It is expected that there will be an increase in spurious emissions when the RF channel is close to multiples of XOSC in TX. We recommend that the level of spurious emissions be evaluated if the RF channel is closer than 1 MHz to multiples of XOSC in TX. | | | |
| Load capacitance (C _L) | | 10 | | pF | | | | |
| ESR | | | 60 | Ω | Simulated over operating conditions | | | |
| Start-up time | | 0.4 | | ms | Depends on crystal | | | |

4.13 High-Speed Clock Input (TCXO)

 $T_A = 25$ °C, VDD = 3.0 V if nothing else is stated

| PARAMETER | MIN | TYP | MAX | UNIT | CONDITION |
|--------------------------------------|-----|-----|-----|------|---|
| Clock frequency | 32 | | 44 | MHz | |
| TCXO with CMOS output | | | | | TCXO with CMOS output directly |
| High input voltage | 1.4 | | VDD | V | coupled to pin EXT_OSC |
| Low input voltage | 0 | | 0.6 | V | |
| Rise / Fall time | | | 2 | ns | |
| Clipped sine output | | | | | TCXO clipped sine output connected |
| Clock input amplitude (peak-to-peak) | 0.8 | | 1.5 | V | to pin EXT_OSC through series capacitor |

4.14 32-kHz Clock Input

 $T_A = 25$ °C, VDD = 3.0 V if nothing else is stated

| PARAMETER | MIN | TYP | MAX | UNIT | CONDITION |
|---|---------|-----|---------|------|-----------|
| Clock frequency | | 32 | | kHz | |
| 32 kHz clock input pin input high voltage | 0.8×VDD | | | V | |
| 32 kHz clock input pin input low voltage | | | 0.2×VDD | V | |



4.15 Low-Speed RC Oscillator

 $T_A = 25$ °C, VDD = 3.0 V if nothing else is stated

| PARAMETER | MIN | TYP | MAX | UNIT | CONDITION |
|--------------------------------------|-----|-------|-----|------|---|
| Frequency | | 32/40 | | kHz | After calibration (calibrated against the high-speed XOSC) |
| Frequency accuracy after calibration | | ±0.1 | | % | Relative to frequency reference (for example, 32-MHz crystal or TCXO) |
| Initial calibration time | | 1.6 | | ms | |

4.16 I/O and Reset

 $T_A = 25$ °C, VDD = 3.0 V if nothing else is stated

| PARAMETER | MIN | TYP | MAX | UNIT | CONDITION |
|---------------------------|---------|-----|---------|------|-----------------------------|
| Logic input high voltage | 0.8×VDD | | | V | |
| Logic input low voltage | | | 0.2×VDD | V | |
| Logic output high voltage | 0.8×VDD | | | V | At 4 mA cutout load or load |
| Logic output low voltage | | | 0.2×VDD | V | At 4-mA output load or less |
| Power-on reset threshold | | 1.3 | | V | Voltage on DVDD pin |

4.17 Temperature Sensor

 $T_A = 25$ °C, VDD = 3.0 V if nothing else is stated

| TA = 23 C, VDD = 3.0 V II Hotrilling else is stated | | | | | | | | | |
|---|-----|------|---------|---------|---|--|--|--|--|
| PARAMETER | MIN | TYP | TYP MAX | | CONDITION | | | | |
| Temperature sensor range | -40 | | 85 | °C | | | | | |
| Temperature coefficient | | 2.66 | | mV / °C | Change in sensor output voltage versus change in temperature | | | | |
| Typical output voltage | | 794 | | mV | Typical sensor output voltage at T _A = 25°C, VDD = 3.0 V | | | | |
| VDD coefficient | | 1.17 | | mV / V | Change in sensor output voltage versus change in VDD | | | | |

The CC1175 device can be configured to provide a voltage proportional to temperature on GPIO1. The temperature can be estimated by measuring this voltage (see Section 4.17). For more information, see the temperature sensor design note (SWRA415).

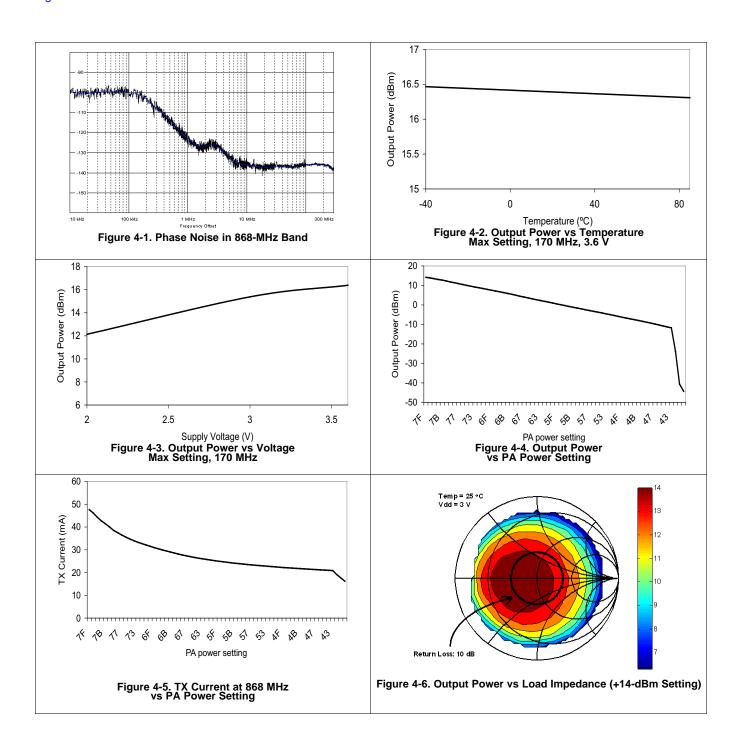


4.18 Typical Characteristics

 $T_A = 25$ °C, VDD = 3.0 V, $f_c = 869.5$ MHz if nothing else is stated.

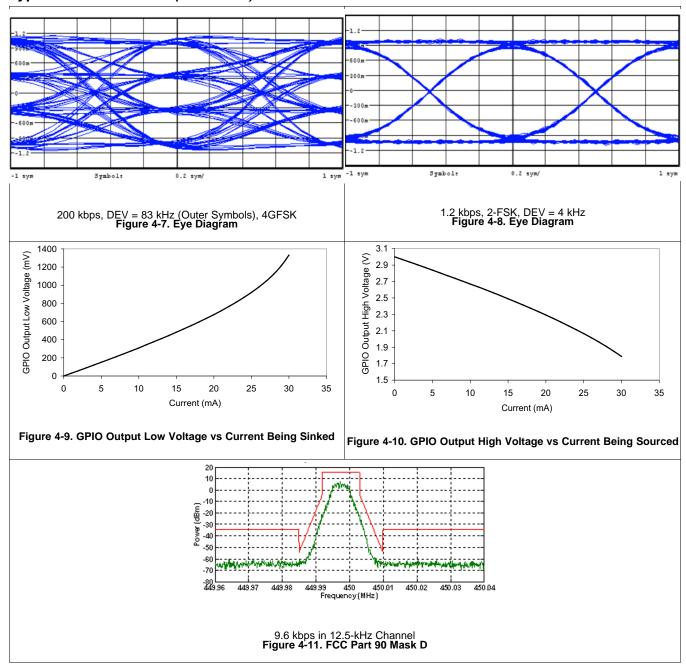
All measurements performed on CC1120EM_868_915 rev.1.0.1, CC1120EM_955 rev.1.2.1, CC1120EM_420_470 rev.1.0.1 or CC1120EM_169 rev.1.2 (fxosc = 32 MHz), and CC1125EM_868_915 rev.1.1.0, CC1125EM_420_470 rev.1.1.0, CC1125EM_169 rev.1.1.0, CC1125EM-Cat1-868 (fxosc = 40 MHz).

Figure 4-6 was measured at the $50-\Omega$ antenna connector.





Typical Characteristics (continued)





5 Detailed Description

5.1 Block Diagram

Figure 5-1 shows the system block diagram of the CC1175 device.

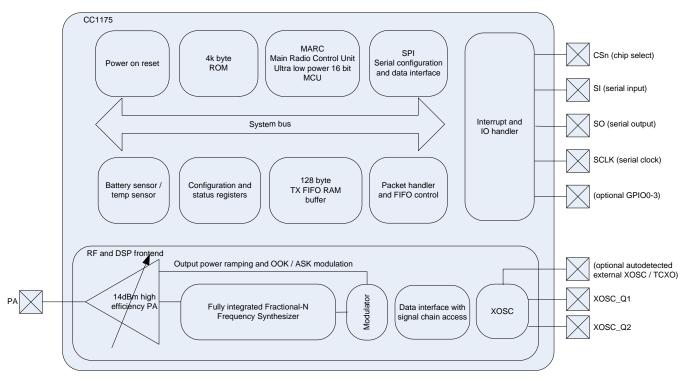


Figure 5-1. System Block Diagram

5.2 Frequency Synthesizer

At the center of the CC1175 device there is a fully integrated, fractional-N, ultra-high-performance frequency synthesizer. The frequency synthesizer is designed for excellent phase noise performance. The system is designed to comply with the most stringent regulatory spectral masks at maximum transmit power.

Either a crystal can be connected to XOSC_Q1 and XOSC_Q2, or a TCXO can be connected to the EXT_XOSC input. The oscillator generates the reference frequency for the synthesizer, as well as clocks for the digital part. If a TCXO is used, the CC1175 device automatically turns on and off the TCXO when needed to support low-power modes.



5.3 Transmitter

The CC1175 transmitter is based on direct synthesis of the RF frequency (in-loop modulation). To achieve effective spectrum usage, the CC1175 device has extensive data filtering and shaping in TX mode to support high throughput data communication in narrowband channels. The modulator also controls power ramping to remove issues such as spectral splattering when driving external high-power RF amplifiers.

The modulator also controls the PA power level to support on/off keying (OOK) and amplitude shift keying (ASK).

5.4 Radio Control and User Interface

The CC1175 digital control system is built around the main radio control (MARC), which is implemented using an internal high-performance, 16-bit ultra-low-power processor. MARC handles power modes, radio sequencing, and protocol timing.

A 4-wire SPI serial interface is used for configuration and data buffer access. The digital baseband includes support for channel configuration, packet handling, and data buffering. The host MCU can stay in power-down mode until a valid RF packet is received. This greatly reduces power consumption. When the host MCU receives a valid RF packet, it burst-reads the data. This reduces the required computing power.

The CC1175 radio control and user interface are based on the widely used CC1101 transceiver. This relationship enables an easy transition between the two platforms. The command strobes and the main radio states are the same for the two platforms.

For legacy formats, the CC1175 device also supports two serial modes.

- Synchronous serial mode: The CC1175 device provides the MCU with a bit clock for sampling input data.
- Transparent mode: The CC1175 device samples the input pin at a configurable rate.

5.5 Low-Power and High-Performance Modes

The CC1175 device is highly configurable, enabling trade-offs between power and performance to be made based on the needs of the application. This data sheet describes two modes, low-power mode and high-performance mode, which represent configurations where the device is optimized for either power or performance.



6 Typical Application Circuit

NOTE

This section is intended only as an introduction.

Very few external components are required for the operation of the CC1175 device. Figure 6-1 shows a typical application circuit. The board layout will greatly influence the RF performance of the CC1175 device. Figure 6-1 does not show decoupling capacitors for power pins.

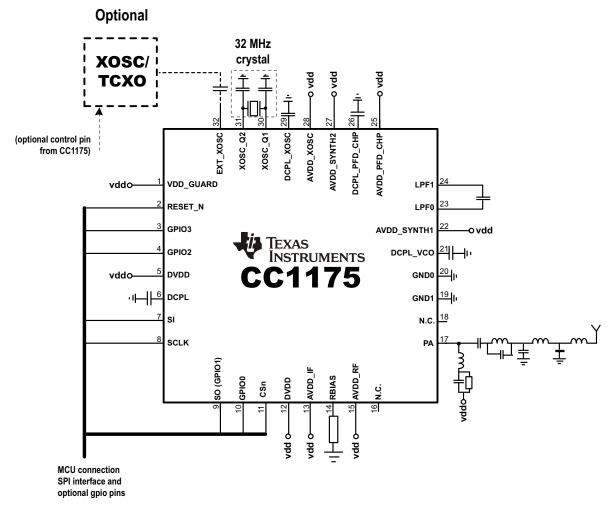


Figure 6-1. Typical Application Circuit

For more information, see the reference designs available for the CC1175 device in Section 7.2, Documentation Support.

7 Device and Documentation Support

7.1 Device Support

7.1.1 Development Support

7.1.1.1 Configuration Software

The CC1175 device can be configured using the SmartRF Studio software (<u>SWRC046</u>). The SmartRF™ Studio software is highly recommended for obtaining optimum register settings, and for evaluating performance and functionality.

7.1.2 Device and Development-Support Tool Nomenclature

To designate the stages in the product development cycle, TI assigns prefixes to the part numbers of all microprocessors (MPUs) and support tools. Each device has one of three prefixes: X, P, or null (no prefix) (for example, CC1175). Texas Instruments recommends two of three possible prefix designators for its support tools: TMDX and TMDS. These prefixes represent evolutionary stages of product development from engineering prototypes (TMDX) through fully qualified production devices and tools (TMDS).

Device development evolutionary flow:

X Experimental device that is not necessarily representative of the final device's electrical specifications and may not use production assembly flow.

P Prototype device that is not necessarily the final silicon die and may not necessarily meet final electrical specifications.

null Production version of the silicon die that is fully qualified.

Support tool development evolutionary flow:

TMDX Development-support product that has not yet completed Texas Instruments internal qualification testing.

TMDS Fully qualified development-support product.

X and P devices and TMDX development-support tools are shipped against the following disclaimer:

"Developmental product is intended for internal evaluation purposes."

Production devices and TMDS development-support tools have been characterized fully, and the quality and reliability of the device have been demonstrated fully. Tl's standard warranty applies.

Predictions show that prototype devices (X or P) have a greater failure rate than the standard production devices. Texas Instruments recommends that these devices not be used in any production system because their expected end-use failure rate still is undefined. Only qualified production devices are to be used.

TI device nomenclature also includes a suffix with the device family name. This suffix indicates the package type (for example, RHB) and the temperature range (for example, blank is the default commercial temperature range) provides a legend for reading the complete device name for any CC1175 device.

For orderable part numbers of CC1175 devices in the QFN package types, see the Package Option Addendum of this document, the TI website (www.ti.com), or contact your TI sales representative.



7.2 Documentation Support

The following document supplements the CC1175 processor. Copies of these documents are available on the Internet at www.ti.com. *Tip:* Enter the literature number in the search box provided at www.ti.com.

SWRR093 CC1175EM 868- to 915-MHz Reference Design

7.3 Community Resources

The following links connect to TI community resources. Linked contents are provided "AS IS" by the respective contributors. They do not constitute TI specifications and do not necessarily reflect TI's views; see TI's Terms of Use.

TI E2E™ Online Community TI's Engineer-to-Engineer (E2E) Community. Created to foster collaboration among engineers. At e2e.ti.com, you can ask questions, share knowledge, explore ideas and help solve problems with fellow engineers.

TI Embedded Processors Wiki Texas Instruments Embedded Processors Wiki. Established to help developers get started with Embedded Processors from Texas Instruments and to foster innovation and growth of general knowledge about the hardware and software surrounding these devices.

7.4 Trademarks

SmartRF, E2E are trademarks of Texas Instruments.

7.5 Electrostatic Discharge Caution



This integrated circuit can be damaged by ESD. Texas Instruments recommends that all integrated circuits be handled with appropriate precautions. Failure to observe proper handling and installation procedures can cause damage.

ESD damage can range from subtle performance degradation to complete device failure. Precision integrated circuits may be more susceptible to damage because very small parametric changes could cause the device not to meet its published specifications.

7.6 Glossary

SLYZ022 — TI Glossary.

This glossary lists and explains terms, acronyms, and definitions.

www.ti.com

8 Mechanical Packaging and Orderable Information

The following pages include mechanical packaging and orderable information. This information is the most current data available for the designated devices. This data is subject to change without notice and revision of this document. For browser-based versions of this data sheet, refer to the left-hand navigation.



PACKAGE OPTION ADDENDUM

11-Dec-2020

PACKAGING INFORMATION

www.ti.com

| Orderable Device | Status (1) | Package Type | Package Drawing | Pins | Package Qty | Eco Plan | Lead finish/ Ball material | MSL Peak Temp | Op Temp (°C) | Device Marking (4/5) | Samples |
|------------------|------------|--------------|--------------------|------|----------------|--------------|-------------------------------|---------------------|--------------|-------------------------|---------|
| CC1175RHBR | ACTIVE | VQFN | RHB | 32 | 3000 | RoHS & Green | NIPDAU NIPDAUAG | Level-3-260C-168 HR | -40 to 85 | CC1175 | Samples |
| CC1175RHBT | ACTIVE | VQFN | RHB | 32 | 250 | RoHS & Green | NIPDAU NIPDAUAG | Level-3-260C-168 HR | -40 to 85 | CC1175 | Samples |

(1) The marketing status values are defined as follows:

ACTIVE: Product device recommended for new designs.

LIFEBUY: TI has announced that the device will be discontinued, and a lifetime-buy period is in effect.

NRND: Not recommended for new designs. Device is in production to support existing customers, but TI does not recommend using this part in a new design.

PREVIEW: Device has been announced but is not in production. Samples may or may not be available.

OBSOLETE: TI has discontinued the production of the device.

(2) RoHS: TI defines "RoHS" to mean semiconductor products that are compliant with the current EU RoHS requirements for all 10 RoHS substances, including the requirement that RoHS substance do not exceed 0.1% by weight in homogeneous materials. Where designed to be soldered at high temperatures, "RoHS" products are suitable for use in specified lead-free processes. TI may reference these types of products as "Pb-Free".

RoHS Exempt: TI defines "RoHS Exempt" to mean products that contain lead but are compliant with EU RoHS pursuant to a specific EU RoHS exemption.

Green: TI defines "Green" to mean the content of Chlorine (CI) and Bromine (Br) based flame retardants meet JS709B low halogen requirements of <=1000ppm threshold. Antimony trioxide based flame retardants must also meet the <=1000ppm threshold requirement.

- (3) MSL, Peak Temp. The Moisture Sensitivity Level rating according to the JEDEC industry standard classifications, and peak solder temperature.
- (4) There may be additional marking, which relates to the logo, the lot trace code information, or the environmental category on the device.
- (5) Multiple Device Markings will be inside parentheses. Only one Device Marking contained in parentheses and separated by a "~" will appear on a device. If a line is indented then it is a continuation of the previous line and the two combined represent the entire Device Marking for that device.
- (6) Lead finish/Ball material Orderable Devices may have multiple material finish options. Finish options are separated by a vertical ruled line. Lead finish/Ball material values may wrap to two lines if the finish value exceeds the maximum column width.

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11-Dec-2020

PACKAGE MATERIALS INFORMATION

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TAPE AND REEL INFORMATION





| | Dimension designed to accommodate the component width |
|----|---|
| В0 | Dimension designed to accommodate the component length |
| K0 | Dimension designed to accommodate the component thickness |
| W | Overall width of the carrier tape |
| P1 | Pitch between successive cavity centers |

QUADRANT ASSIGNMENTS FOR PIN 1 ORIENTATION IN TAPE



*All dimensions are nominal

| Device | Package Type | Package Drawing | | | Reel Diameter (mm) | Reel Width W1 (mm) | A0 (mm) | B0 (mm) | K0 (mm) | P1 (mm) | W (mm) | Pin1 Quadrant |
|------------|-----------------|--------------------|----|------|--------------------------|--------------------------|------------|------------|------------|------------|-----------|------------------|
| CC1175RHBR | VQFN | RHB | 32 | 3000 | 330.0 | 12.4 | 5.3 | 5.3 | 1.5 | 8.0 | 12.0 | Q2 |

www.ti.com 27-Oct-2021



*All dimensions are nominal

| Device | Device Package Type | | Pins | SPQ | Length (mm) | Width (mm) | Height (mm) | |
|------------|---------------------|-----|------|------|-------------|------------|-------------|--|
| CC1175RHBR | VQFN | RHB | 32 | 3000 | 350.0 | 350.0 | 43.0 | |

5 x 5, 0.5 mm pitch

PLASTIC QUAD FLATPACK - NO LEAD



Images above are just a representation of the package family, actual package may vary. Refer to the product data sheet for package details.

4224745/A





PLASTIC QUAD FLATPACK - NO LEAD



NOTES:

- 1. All linear dimensions are in millimeters. Any dimensions in parenthesis are for reference only. Dimensioning and tolerancing per ASME Y14.5M.
 2. This drawing is subject to change without notice.
- 3. The package thermal pad must be soldered to the printed circuit board for thermal and mechanical performance.



PLASTIC QUAD FLATPACK - NO LEAD



NOTES: (continued)

- 4. This package is designed to be soldered to a thermal pad on the board. For more information, see Texas Instruments literature number SLUA271 (www.ti.com/lit/slua271).
- Vias are optional depending on application, refer to device data sheet. If any vias are implemented, refer to their locations shown on this view. It is recommended that vias under paste be filled, plugged or tented.



PLASTIC QUAD FLATPACK - NO LEAD



NOTES: (continued)

6. Laser cutting apertures with trapezoidal walls and rounded corners may offer better paste release. IPC-7525 may have alternate design recommendations.



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